

Search Notes

Application/Control No.

10/506,497

Examiner

Patrick J. Lee

Applicant(s)/Patent under
Reexamination

NYGARD, EINAR

Art Unit

2878

SEARCHED

Class	Subclass	Date	Examiner
250	208.1, 214.1, 214R	3/8/06 3/10/06	PL
438	57-60	3/10/2006	PL
438	64-67	3/10/2006	PL
438	73-81	3/10/2006	PL
Updated	search	6/9/2006	PL
Updated	search	6/14/2006	PL
257	222, 225	6/14/2006	PL
257	232	6/14/2006	PL
257	257-258	6/14/2006	PL
257	288-291	6/14/2006	PL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Interference search attached		6/14/2006	PL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted w/ S. Allen AU 2878 CL 250	3/8/2006	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	3/8/2006	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	3/10/2006	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	6/9/2006	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	6/14/2006	PL